

<b>Notice of References Cited</b>	Application/Control No. 10/829,386		Applicant(s)/Patent Under Reexamination AN ET AL.	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,757,765 A	05-1998	Chen, Yao-Kuo	720/719
*	B	US-5,982,737 A	11-1999	Takagishi et al.	369/275.1
*	C	US-6,481,484 B1	11-2002	Isshiki, Yuzuru	156/556
*	D	US-2003/0039201 A1	02-2003	Fujii et al.	369/283
*	E	US-6,532,210 B2	03-2003	Park, Jun-min	369/282
*	F	US-2003/0091781 A1	05-2003	Arakawa et al.	428/64.4
*	G	US-2004/0103423 A1	05-2004	Chuang, Cheng-Chieh	720/719
*	H	US-2004/0205806 A1	10-2004	Brown, Johnny L.	720/719
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.